



The Institution of Electronics and
Telecommunication Engineers



IETE Journal of Education

Volume 54 • No. 1 • Jan-Jun 2013

www.ietejournals.org

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IETE JOURNAL OF EDUCATION

Published semiannually by the Institution of Electronics and Telecommunication Engineers

JANUARY - JUNE, 2013 | VOLUME - 54 | ISSUE - 1

Contents

Message from the President	3
From the Editor-in-Chief's Desk	4
<i>Raj Senani</i>	
Articles	
A Pulse Position Sampled Multiplier	5
<i>K C Selvam</i>	
A Few Insights into Error Function	9
<i>P Hari Krishna Prasad</i>	
Low Pass and Bandpass Microwave Filters	12
<i>Vishakha Dang</i>	
Bipolar Multiplexed Pulse Width Modulation	18
<i>P Hari Krishna Prasad</i>	
OFDM and its Major Concerns: A Study with Way Out	26
<i>Rajiv Saxena and Hem Dutt Joshi</i>	
Built in Self Repair Architecture for SRAM using Redundancy Logic	50
<i>N M Siva Mangai</i>	
IETE Information	
Distinguished IETE Alumni	60



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IETE JOURNAL OF EDUCATION

Published semiannually by the Institution of Electronics and Telecommunication Engineers

JULY-DECEMBER 2013 | VOLUME - 54 | ISSUE - 2

Contents

SUBSCRIBED

Message from the President	63
From the Editor-in-Chief's Desk	64
<i>Raj Senani</i>	
Articles	
Conditions for the Maximum Power Transfer	65
<i>T S Rathore</i>	
Measurement of Phase Angle and Power Factor by Multiplexing Technique	73
<i>K C Selvam</i>	
Injection Locked Oscillator: A Review	77
<i>Subhradeep Pal and B N Biswas</i>	
Performance Analysis of Particle Filter for Launch Vehicle Trajectory	83
<i>Leela Kumari B and K Padma Raju</i>	
Canceling the Power Frequency Magnetic and Electric Fields of Power Lines	90
<i>Mohamed M Saied</i>	
UWB Interference Probability on Wi-MAX Receiver (Case Study of Coexistence Issue)	100
<i>Rajesh D Thakare and Kishore D Kulat</i>	
Spatial and Frequency Domain Filters for Restoration of Noisy Images	108
<i>Paras Jain and Vipin Tyagi</i>	



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